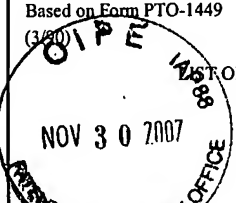


| | | |
|--|--|---------------------------------|
| Based on Form PTO-1449 (3/80)  | ATTY. DOCKET NO. 455610-2590.1 | SERIAL NO. 10/673,736 |
| | APPLICANT Martin Thomas Miller | |
| | FILING DATE September 29, 2003 | GROUP 2117 |

U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|---------------------|----|-----------------|------|------|-------|----------|-------------------------------|
| | AA | | | | | | |
| | AB | | | | | | |
| | AC | | | | | | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
| | AI | | | | | | |
| | AJ | | | | | | |
| | AK | | | | | | |

FOREIGN PATENT DOCUMENTS

| | | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
|--|----|-----------------|------|---------|-------|----------|-------------|----|
| | | | | | | | YES | NO |
| | AL | | | | | | | |
| | AM | | | | | | | |
| | AN | | | | | | | |
| | AO | | | | | | | |
| | AP | | | | | | | |

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

| | | |
|--|----|--|
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| | AR | Communications Signal Analyzer, Communications Eye-diagram Measurements Software, Tektronix website (http://www.tektronix.com), May 12, 2003 |
| | AS | RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix website(www.tektronix.com/accessories), September 20, 2002 |
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| | AU | A New Digital PLL at the Technische Universitaet Berlin, The Cooperation Project, (http://www.tdl.com/~gottsch/tuberlin.htm), August 5, 2003 |
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| | | Williams, Michael, "A Discussion of Methods for Measuring Low-Amplitude Jitter", International Test Conference, Paper 28.1, pp. 646-652, 1995 IEEE |
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EXAMINER

DATE CONSIDERED

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.